# Time of flight identification of ions for ERL

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#### Why an Ion TOF Spectrometer?

- Scattering on the dilute gas by the beam produces positively charged ions
- lons can then accumulate in the beam potential
- Possible 'cascade' effect
  - Disturb the motion of the beam
  - Widen the cross section (especially undesirable in ERL)

## How this can happen, 1

- Fast ion instability
  - lons oscillate in the electron beam and vice versa
  - Coupled system becomes unstable
  - Large oscillations or increase in transverse beam size

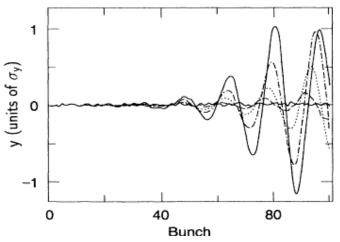


FIG. 1. Vertical beam centroid as a function of bunch number after a distance of 0 m (solid curve), 750 m (dashed curve), 1125 m (dotted curve), 1500 m (dash-dotted curve), and 1875 m (solid curve), respectively, for a train of 100 bunches, with an atomic mass of 28 (carbonmonoxide) and a pressure of  $10^{-5}$  Torr in the arcs of the PEP-II HER.

Raubenheimer and Zimmerman Phys. Rev. E **52** 5487 (1995)

## How this can happen, 2

- Nonlinear focusing
  - Accumulated ions focus electrons non-linearly as a function of the electron's distance from the beam center
  - Emittance growth

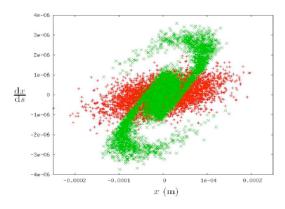


FIG. 8: Electron beam phase-space distribution after transversing the 100m ion field with  $\beta^* = 100$ m at its center. Dark-red +: phase space in a free drift, Light-green ×: phase space for motion through the ion field.

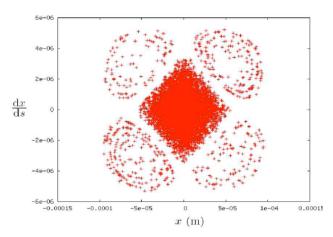
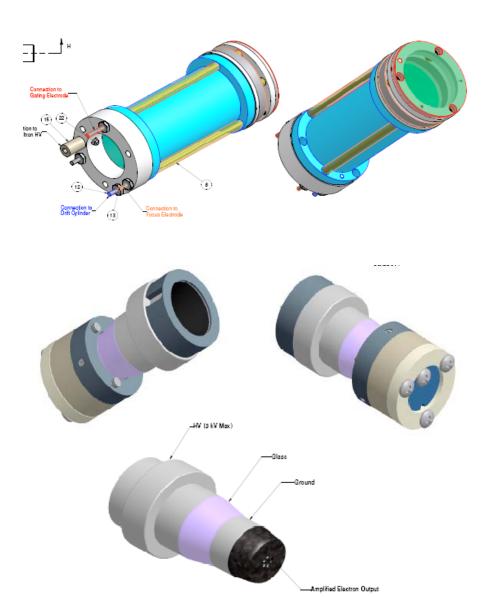


FIG. 15: Electron beam phase-space plot after transversing a 34m long region with medium high ion density 1000 times.

Hoffstaetter and Spethmann http://arxiv.org/abs/0706.2897

#### **TOF Spectrometer**

- Measure the composition of the ion gas near the beam
- Determine charge state and type of ions
  - lons enter the TOFS chamber, are accelerated through a well-defined potential, then their velocities are measured
  - Determine mass to charge ratio



#### **Timeline**

- Electronics assembly
  - Gate ring circuit, HV divider-> finished
- Ion source for characterization
  - June 20
- Characterize detector
  - Correlation of measured voltages to measured ion density
- SIMION simulation of ion optics
- Trial installation on CESR?
- Test in ERL prototype injector